MULTI-FREQUENCY DIRECT SAMPLING METHOD FOR IMAGING SHORT LINEAR PERFECTLY CONDUCTING CRACKS

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ABSTRACT
We apply direct sampling method (DSM) for identifying location of short linear perfectly conducting cracks. For this, we design a multi-frequency indicator function of DSM and investigate its structure by establishing a relationship with Bessel function of integer order and the length of cracks. Simulation results are exhibited to verify the investigated structure of indicator function.

REFERENCES